



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#6 IDS
DFA/16/17/18
9-3-02

Applicant(s): Gouheng, Zhao et al.
Assignee: KLA-Tencor Corporation
Title: System for Measuring Periodic Structures
Application No.: 09/742,029 Filing Date: December 20, 2000
Examiner: Not Yet Assigned Group Art Unit: 2877
Docket No.: M-10696 US

San Francisco, California

COMMISSIONER FOR PATENTS
Washington, D.C. 20231

**INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(c) WITH
CERTIFICATION UNDER 37 C.F.R. § 1.97(e)(1)**

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant wishes to call the documents listed on the enclosed Form PTO-1449 (1 page) to the Examiner's attention for the above-identified patent application. Copies of the listed documents are enclosed. The documents were first cited by the International Search Authority in a corresponding foreign Application No. PCT/US01/49259 on July 9, 2002.

Citation of the above documents shall not be construed as:

1. an admission that the documents are necessarily prior art with respect to the instant invention;
2. a representation that a search has been made, other than as described above; or
3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

RECEIVED
AUG 20 2002
TECHNOLOGY CENTER 2800

LAW OFFICES OF
SKJERNEN MORRILL LLP
3 EMBARCADERO CENTER
28TH FLOOR
SAN FRANCISCO, CA 94111
(415) 217-6000
FAX (415) 434-0646

The undersigned hereby certifies in accordance with § 1.97(e)(1) that each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.

Respectfully submitted,


James S. Hsue

Attorney for Applicant(s)
Reg. No. 29,545

8/12/02
Date:

EXPRESS MAIL LABEL NO:

EL 947771752 US